

### CLAIMS

What is claimed is:

1. (Currently amended) A slurry for chemical mechanical polishing (CMP) of a metal comprising film, comprising a solution including:  
at least one halide ion, and  
at least one diatomic halogen molecule selected from the group consisting of  $I_2$ ,  $Br_2$ ,  $Cl_2$  and  $F_2$  or interhalogen compounds which comprise diatomic molecules which combine different halogen atoms, and  
particles comprising silica, alumina, titania, yttria, zirconia, zinc oxide, porous silica, or alumina cores or silica cores coated with alumina, yttria, titania, or a polymer.
2. (Previously presented) The slurry of claim 1, wherein said diatomic halogen molecule comprises  $I_2$ .
3. (Original) The slurry of claim 1, wherein said halide ion comprises  $I^-$ .
4. (Previously presented) The slurry of claim 1, wherein said diatomic halogen molecule is formed from at least one chemical which forms said halogen *in-situ* in said the slurry.
5. (Previously presented) The slurry of claim 4, wherein said diatomic halogen molecule is  $I_2$ .

6. (Previously presented) The slurry of claim 1, wherein said diatomic halogen molecule comprises  $\text{Br}_2$  or  $\text{Cl}_2$ .
7. Cancelled
8. (Original) The slurry of claim 1, further comprising at least one surfactant.
9. (Original) The slurry of claim 1, further comprising at least one polymer additive.
10. Cancelled
11. (Original) The slurry of claim 1, further comprising at least one salt.
12. (Withdrawn) A method for chemical mechanical polishing (CMP) a metal comprising containing film, comprising the steps of:  
providing a slurry including at one halide ion and at least one halogen species, said slurry reacting with said metal film to form a surface layer on said film, and removing said surface layer.
13. (Withdrawn) The method of claim 12, wherein abrasive particles embedded in a polishing pad, or an inorganic layer coated on a polymeric pad is used for said removing step.

14. (Withdrawn) The method of claim 13, wherein said metal film comprising film includes copper.
15. (Withdrawn) The method of claim 12, wherein said halogen comprises  $I_2$ .
16. (Withdrawn) The method of claim 12, wherein said halide ion comprises  $I_2$ .
17. (Withdrawn) The method of claim 12, wherein said halogen comprises  $Br_2$  or  $Cl_2$ .
18. (Withdrawn) The method of claim 12, wherein said slurry further comprises at least one surfactant or polymer additive.
19. (Withdrawn) The method of claim 12, wherein said slurry includes at least one interhalogen compound.
20. (Withdrawn) The method of claim 12, wherein said slurry includes at least one surfactant.